

2nd probe card

Wafer ID: 05A4

Start date: 2024-06-07

There were 70 total error messages and 47 actual errors in 1 wafer. 19 were repeats and will not be shown below.

Number of scan chain errors: 4

Number of analog scan failures: 1

Number of digital scan failures: 6

Number of VDD errors: 4

Number of chips with dead pixels: 4

Number of DAQ function program terminations: 0

Number of programming errors: 0

Number of DAQ digital scan errors: 2

Number of DAC calibration errors: 2

Number of temperature measurement errors: 1

Number of LDO measurement errors: 0

Number of IREF trimming failures: 0

Number of threshold scan failures: 2

Number of overvoltage trip errors: 0

Number of data merging errors: 2

16 chip(s) did not complete testing (chip ID(s): 52, A2, 36, B6, 17, 68, 78, 98, D8, 39, 3A, 9A, 4B, 5C, 9C, 7D).

Total number of dead pixels: 5 (of 145152 in 1 wafer)

Other errors (0):

